

**QUALCOMM® QUICK CHARGE™ 3.0 TECHNOLOGY**

**HIGH VOLTAGE DEDICATED CHARGING PORT  
VERIFICATION**

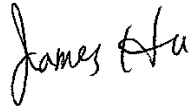
**ISSUED BY  
UL VERIFICATION SERVICES INC.**

<b>CERTIFICATE NO</b>	▶ 4787357871-2
<b>SPECIFICATION</b>	▶ Qualcomm HVDCP Interface Specification Revision J
<b>APPROVAL DATE</b>	▶ April 19, 2016
<b>APPROVAL TYPE</b>	▶ ORIGINAL ASSESSMENT
<b>CERTIFICATE HOLDER</b>	▶ Dialog Semiconductor Inc. ▶ 675 Campbell Technology Pkwy, Suite 150 ▶ Campbell, CA 95008 USA
<b>TYPE OF EQUIPMENT</b>	▶ Chipset Reference Design
<b>CLASS OF EQUIPMENT</b>	▶ CLASS A
<b>TRADE NAME AND MODEL</b>	▶ Dialog Semiconductor ▶ iW636
<b>MEASUREMENT FACILITIES</b>	
<b>LABORATORY NAME AND ADDRESS</b>	▶ UL Verification Services Inc. ▶ 47266 Benicia Street ▶ Fremont, CA 94538 ▶ USA

*Verification of equipment means only that the equipment has met the requirements of the above-noted specification. Trademark applications and agreements regarding the use of Quick Charge 2.0 Logo, are acted on accordingly by Qualcomm Technologies, Inc. This certificate is issued on condition that the holder complies and will continue to comply with the Quick Charge 2.0 program requirements established by Qualcomm Technologies, Inc. The equipment for which this certificate is issued shall not bear the Qualcomm Quick Charge 2.0 Logo unless the equipment complies with the applicable technical specifications and agreements issued by Qualcomm Technologies, Inc. as applicable to the Type Of Equipment and Class Of Equipment designated above.*

*I hereby attest that the subject equipment was tested and found in compliance with the above-noted specification.*

**ISSUED BY:**



James Hu  
Project Engineer, UL Taiwan Co., Ltd.

**ISSUED ON:**

▶ April 19, 2016

